



Best Paper Award

The 2020 International Symposium on VLSI Design, Automation and Test (VLSI-DAT)

Presents

Best Paper Award

to

**Jinn-Shyan Wang, Chien-Tung Liu and
Chao-Hsiang Wang**

National Chung Cheng University

For the paper entitled

**Low-Active-Energy and Low-Standby-Power Sub-threshold ROM for
IoT Edge Sensing Systems**

An Award Committee is formed for the selection of the Best Paper Award. The selection criteria of the award include the technical content and writing quality of the paper as well as the quality of the presentation at the symposium.

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